

### **Asynchronous fault detection in IEEE P1687 instrument network**

**Shibin, Konstantin; Devadze, Sergei; Jutman, Artur** IEEE 23rd North Atlantic Test Workshop : 14-16 May 2014, Binghampton, New York : proceedings 2014 / p. 73-78 : ill

### **BASTION : board and SoC test instrumentation for ageing and no failure found**

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### **Health management for self-aware SoCs based on IEEE 1687 infrastructure**

**Shibin, Konstantin; Devadze, Sergei; Jutman, Artur; Grabmann, Martin; Pricken, Robin** IEEE Design & Test 2017 / p. 27-35 : ill  
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### **IEEE 1687 compliant ecosystem for embedded instrumentation access and in-field health monitoring**

**Tšertov, Anton; Jutman, Artur; Shibin, Konstantin; Devadze, Sergei** IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 9 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532559>

### **IEEE P1687 IJTAG demonstrator on FPGA**

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**Jutman, Artur; Devadze, Sergei; Aleksejev, Jevgeni** 6th International Workshop on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC) : 20-22 June 2011, Montpellier, France 2011 / [4] p.: ill <https://ieeexplore.ieee.org/document/5981520>

### **On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks**

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### **On-line fault classification and handling in IEEE1687 based fault management system for complex SoCs**

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### **Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687**

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